



1 Cover Page

RF Exposure REPORT

Application No.: SHEM1901000065CR
FCC ID: YCP-MB1293000
IC: 8976A-MB1293000
Applicant: STMicronics SAS
Address of Applicant: 190 Avenue Celestin Coq, CS 60004, 13016 Rousset Cedex, France
Manufacturer: STMicronics
Address of Manufacturer: 190 Avenue Celestin Coq, CS 60004, 13016 Rousset Cedex, France
Factory: Embest Technology Co., Ltd.
Address of Factory: Tower B 4/F, Shanshui Building, Nanshan Yungu Innovation Industry Park, Liuxian Ave. No. 1183, Taoyuan street, Nanshan Distric, Shenzhen, China

Equipment Under Test (EUT):

EUT Name: P-NUCLEO-WB55
Model No.: MB1293C-02
Trade mark: STMicronics
Standard(s) : FCC Rules 47 CFR §2.1091
KDB447498 D01 General RF Exposure Guidance v06
RSS-102 Issue 5 (March 2015)

Date of Receipt: 2019-01-09
Date of Test: 2019-01-15 to 2019-01-18
Date of Issue: 2019-02-28

Test Result:	Pass*
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* In the configuration tested, the EUT complied with the standards specified above.

Parlam Zhan

Parlam Zhan
E&E Section Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.



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Attention: To check the authenticity of testing /inspection report & certificate, please contact us at telephone: (86-755) 8307 1443, or email: CN.Doccheck@sgs.com

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd.
Testing Center E&E (Shanghai)

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Revision Record			
Version	Description	Date	Remark
00	Original	2019-02-28	/

Authorized for issue by:				
		Bill Wu		
		Bill Wu / Project Engineer		
		Parlam Zhan		
		Parlam Zhan / Reviewer		



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3 General Information

3.1 General Description of E.U.T.

Power supply:	DC 5V power by PC
Test voltage:	AC120V 60Hz

3.2 Details of E.U.T.

Antenna Gain	1.95dBi
Antenna Type	PCB Antenna
Channel Spacing	2MHz
Modulation Type	GFSK
Number of Channels	40
Operation Frequency	2402MHz to 2480MHz



3.3 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shanghai Branch

588 West Jindu Road, Xinqiao, Songjiang, 201612 Shanghai, China.

Tel: +86 21 6191 5666

Fax: +86 21 6191 5678

3.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **CNAS (No. CNAS L0599)**

CNAS has accredited SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

- **NVLAP (Certificate No. 201034-0)**

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. is accredited by the National Voluntary Laboratory Accreditation Program (NVLAP). Certificate No. 201034-0.

- **FCC –Designation Number: CN5033**

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. has been recognized as an accredited testing laboratory.

Designation Number: CN5033. Test Firm Registration Number: 479755.

- **Industry Canada (IC) – IC Assigned Code: 8617A**

The 3m Semi-anechoic chamber of SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 8617A-1.

- **VCCI (Member No.: 3061)**

The 3m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-13868, C-14336, T-12221, G-10830 respectively.



4 Test Standards and Limits

4.1 FCC Radiofrequency radiation exposure limits:

According to §1.1310, the limit for general population/uncontrolled exposures

Frequency	Power density(mW/cm ²)	Averaging time(minutes)
300MHz~1.5GHz	f/1500	30
1.5GHz~100GHz	1.0	30

4.2 IC Radiofrequency radiation exposure limits:

According to RSS-102 section 2.5.2, RF exposure evaluation is required if the separation distance between the user and/or bystander and the device's radiating element is greater than 20 cm, except when the device operates as follows:

below 20 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1 W (adjusted for tune-up tolerance);

- at or above 20 MHz and below 48 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than $4.49/f^{0.5}$ W (adjusted for tune-up tolerance), where f is in MHz;
- at or above 48 MHz and below 300 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 0.6 W (adjusted for tune-up tolerance);
- at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than $1.31 \times 10^{-2} f^{0.6834}$ W (adjusted for tune-up tolerance), where f is in MHz;
- at or above 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 5 W (adjusted for tune-up tolerance).

For 2.4G device, the limit of worse case is 2.68 W



5 Measurement and Calculation

5.1 Maximum transmit power

The Power Data is based on the RF Test Report SHEM190100006501.

Test Data:

Test Mode	Test Channel	Power[dBm]	Peak Power (mW)
BLE	2402	-6.65	0.22
BLE	2440	-3.65	0.43
BLE	2480	-3.46	0.45

5.2 RF Exposure Calculation

The max conducted output power is 0.45mW;

The best case gain of the antenna is 1.95dBi. 1.95 dBi logarithmic terms convert to numeric result is nearly 1.57

For FCC:

- $\frac{PG}{4R^2\pi}$
- 1) According to the formula $S = \frac{PG}{4R^2\pi}$, we can calculate S which is MPE.
 - 2) Note:
 - 3) P (Watts)
 - 4) G (Antenna gain in numeric)
 - 5) R = distance to the center of radiation of antenna (in meter) = 20cm
 - 6) MPE limit = 1mW/cm²

$$S = \frac{PG}{4R^2\pi} = 0.0001\text{mW/cm}^2 < 1\text{mW/cm}^2$$

For IC:

$$E.I.R.P. = P \times G = 0.00045 \times 1.57 = 0.001\text{W} < 2.68\text{W}$$

So the device is exclusion from SAR test.

--End of the Report--